

Date: September 29, 2004
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>		ATTY. DOCKET NO. BDL-446XX		APPLICATION NO. 10/765,416	
		APPLICANT: Jean-Michel Larrieu, et al.			
		FILING DATE January 27, 2004		TC ART UNIT 3753	

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION/ ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE
TJK	US 6,397,581 B1	6/4/2002	Vidal, et al.	60	267	
TJK	US 4,838,031	6/13/1989	Cramer	60	753	
	US					
	US					
	US					
	US					
	US					

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
TJK	WO 00/28202	5/18/2000	PCT				X

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)		

EXAMINER DMWeller	DATE CONSIDERED 3/4/05
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*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

CLG:kmw/311781-1

Date: January 27, 2004

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U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION/ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE
TJW	US 6,151,887 A	11/28/2000	Haidn, et al.			
	US					
	US					
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FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
TJW	FR 2 553 148 A	4/12/1985	France				X
TJW	FR 2 785 664 A	5/12/2000	France				X

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)	

EXAMINER <i>J. Wallberg</i>	DATE CONSIDERED <i>3/4/05</i>
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*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.